

**HYB25DC256163CE-4**  
**HYB25DC256163CE-5**  
**HYB25DC256163CE-6**

*256-Mbit Double-Data-Rate SGRAM*  
*Green Product*



## Internet Data Sheet

*Rev. 1.1*

HYB25DC256163CE  
256-Mbit Double-Data-Rate SGRAM

HYB25DC256163CE-4, HYB25DC256163CE-5, HYB25DC256163CE-6

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Page	Subjects (major changes since last revision)
All	Adapted internet edition
All	Added new speedsort -4
<b>Previous Revision: 2007-01, Rev. 1.0</b>	

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# 1 Overview

This chapter lists all main features of the product family HYB25DC256163CE and the ordering information.

## 1.1 Features

- Double data rate architecture: two data transfers per clock cycle
- Bidirectional data strobe (DQS) is transmitted and received with data, to be used in capturing data at the receiver
- DQS is edge-aligned with data for reads and is center-aligned with data for writes
- Differential clock inputs (CK and  $\overline{\text{CK}}$ )
- Four internal banks for concurrent operation
- Data mask (DM) for write data
- DLL aligns DQ and DQS transitions with CK transitions
- Commands entered on each positive CK edge; data and data mask referenced to both edges of DQS
- Burst Lengths: 2, 4, or 8
- CAS Latency: 3
- Auto Precharge option for each burst access
- Auto Refresh and Self Refresh Modes
- 7.8  $\mu\text{s}$  Maximum Average Periodic Refresh Interval
- 2.5 V (SSTL\_2 compatible) I/O
- $V_{\text{DDQ}} = 2.5 \text{ V} \pm 0.2 \text{ V}$  (DDR200, DDR266, DDR333);  $V_{\text{DDQ}} = 2.6 \text{ V} \pm 0.1 \text{ V}$  (DDR400, DDR500)
- $V_{\text{DD}} = 2.5 \text{ V} \pm 0.2 \text{ V}$  (DDR200, DDR266, DDR333);  $V_{\text{DD}} = 2.6 \text{ V} \pm 0.1 \text{ V}$  (DDR400, DDR500)
- PG-TSOP11-66 package
- Lead- and halogene-free = green product

**TABLE 1**  
Performance

Part Number Speed Code			-4	-5	-6	Unit
Speed Grade			DDR500	DDR400B	DDR333	—
Max. Clock Frequency	@CL3	$f_{\text{CK3}}$	250	200	166	MHz



HYB25DC256163CE  
256-Mbit Double-Data-Rate SGRAM

## 1.1.1 Description

The 256-Mbit Double-Data-Rate SGRAM is a high-speed CMOS, dynamic random-access memory containing 268,435,456 bits. It is internally configured as a quad-bank DRAM.

The 256-Mbit Double-Data-Rate SGRAM uses a double-data-rate architecture to achieve high-speed operation. The double data rate architecture is essentially a 2n prefetch architecture with an interface designed to transfer two data words per clock cycle at the I/O pins. A single read or write access for the 256-Mbit Double-Data-Rate SGRAM effectively consists of a single 2n-bit wide, one clock cycle data transfer at the internal DRAM core and two corresponding n-bit wide, one-half-clock-cycle data transfers at the I/O pins.

A bidirectional data strobe (DQS) is transmitted externally, along with data, for use in data capture at the receiver. DQS is a strobe transmitted by the DDR SGRAM during Reads and by the memory controller during Writes. DQS is edge-aligned with data for Reads and center-aligned with data for Writes.

The 256-Mbit Double-Data-Rate SGRAM operates from a differential clock (CK and  $\overline{\text{CK}}$ ; the crossing of CK going HIGH and  $\overline{\text{CK}}$  going LOW is referred to as the positive edge of CK). Commands (address and control signals) are registered at every positive edge of CK. Input data is registered on both edges of DQS, and output data is referenced to both edges of DQS, as well as to both edges of CK. Read and write accesses to the DDR SGRAM are burst oriented; accesses start at a selected location and continue for a programmed number of locations in a programmed sequence. Accesses begin with the registration of an Active command, which is then followed by a Read or Write command. The address bits registered coincident with the Active command are used to select the bank and row to be accessed. The address bits registered coincident with the Read or Write command are used to select the bank and the starting column location for the burst access.


The DDR SGRAM provides for programmable Read or Write burst lengths of 2, 4 or 8 locations. An Auto Precharge function may be enabled to provide a self-timed row precharge that is initiated at the end of the burst access. As with standard SDRAMs, the pipelined, multibank architecture of DDR SGRAMs allows for concurrent operation, thereby providing high effective bandwidth by hiding row precharge and activation time.

An auto refresh mode is provided along with a power-saving power-down mode. All inputs are compatible with the Industry Standard for SSTL\_2. All outputs are SSTL\_2, Class II compatible.

*Note: The functionality described and the timing specifications included in this data sheet are for the DLL Enabled mode of operation.*

### TABLE 2

#### Ordering Information for Lead free Products

Product Type	Organisation	Clock (MHz)	Package	Note
HYB25DC256163CE-4	×16	250	PG-TSOP11-66-2 	1)
HYB25DC256163CE-5		200		
HYB25DC256163CE-6		166		

1) RoHS Compliant Product: Restriction of the use of certain hazardous substances (RoHS) in electrical and electronic equipment as defined in the directive 2002/95/EC issued by the European Parliament and of the Council of 27 January 2003. These substances include mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls and polybrominated biphenyl ethers.



## 2 Chip Configuration

The chip configuration of a DDR SGRAM is listed by function in **Table 3**. The abbreviations used in the Pin#/Buffer# column are explained in **Table 4** and **Table 5** respectively. The chip numbering for TSOP is depicted in **Figure 1**.

**TABLE 3**  
Chip Configuration

Ball#	Name	Pin Type	Buffer Type	Function
<b>Clock Signals</b>				
45	CK	I	SSTL	<b>Clock Signal</b>
46	$\overline{\text{CK}}$	I	SSTL	<b>Complementary Clock Signal</b>
44	CKE	I	SSTL	<b>Clock Enable</b>
<b>Control Signals</b>				
23	$\overline{\text{RAS}}$	I	SSTL	<b>Row Address Strobe</b>
22	$\overline{\text{CAS}}$	I	SSTL	<b>Column Address Strobe</b>
21	$\overline{\text{WE}}$	I	SSTL	<b>Write Enable</b>
24	$\overline{\text{CS}}$	I	SSTL	<b>Chip Select</b>
<b>Address Signals</b>				
26	BA0	I	SSTL	<b>Bank Address Bus 2:0</b>
27	BA1	I	SSTL	
29	A0	I	SSTL	<b>Address Bus 11:0</b>
30	A1	I	SSTL	
31	A2	I	SSTL	
32	A3	I	SSTL	
35	A4	I	SSTL	
36	A5	I	SSTL	
37	A6	I	SSTL	
38	A7	I	SSTL	
39	A8	I	SSTL	
40	A9	I	SSTL	
28	A10	I	SSTL	
	AP	I	SSTL	
41	A11	I	SSTL	
42	A12	I	SSTL	<b>Address Signal 12</b> <i>Note: Module based on 256 Mbit or larger dies</i>
	NC	NC	—	<i>Note: Module based on 128 Mbit or smaller dies</i>
17	A13	I	SSTL	<b>Address Signal 13</b> <i>Note: 1 Gbit based module</i>
	NC	NC	—	<i>Note: Module based on 512 Mbit or smaller dies</i>



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Ball#	Name	Pin Type	Buffer Type	Function
<b>Data Signals ×16 Organization</b>				
2	DQ0	I/O	SSTL	<b>Data Signal 15:0</b>
4	DQ1	I/O	SSTL	
5	DQ2	I/O	SSTL	
7	DQ3	I/O	SSTL	
8	DQ4	I/O	SSTL	
10	DQ5	I/O	SSTL	
11	DQ6	I/O	SSTL	
13	DQ7	I/O	SSTL	
54	DQ8	I/O	SSTL	
56	DQ9	I/O	SSTL	
57	DQ10	I/O	SSTL	
59	DQ11	I/O	SSTL	
60	DQ12	I/O	SSTL	
62	DQ13	I/O	SSTL	
63	DQ14	I/O	SSTL	
65	DQ15	I/O	SSTL	
<b>Data Strobe ×16 Organization</b>				
51	UDQS	I/O	SSTL	<b>Data Strobe Upper Byte</b>
16	LDQS	I/O	SSTL	<b>Data Strobe Lower Byte</b>
<b>Data Mask ×16 Organization</b>				
47	UDM	I	SSTL	<b>Data Mask Upper Byte</b>
20	LDM	I	SSTL	<b>Data Mask Lower Byte</b>
<b>Power Supplies</b>				
49	$V_{REF}$	AI	—	<b>I/O Reference Voltage</b>
3, 9, 15, 55, 61	$V_{DDQ}$	PWR	—	<b>I/O Driver Power Supply</b>
1, 18, 33	$V_{DD}$	PWR	—	<b>Power Supply</b>
6, 12, 52, 58, 64	$V_{SSQ}$	PWR	—	<b>Power Supply</b>
34	$V_{SS}$	PWR	—	<b>Power Supply</b>
<b>Not Connected ×16 Organization</b>				
14, 17, 19, 25, 42, 43, 50, 53	NC	NC	—	<b>Not Connected</b>

HYB25DC256163CE  
256-Mbit Double-Data-Rate SGRAM**TABLE 4**  
**Abbreviations for Pin Type**

Abbreviation	Description
I	Standard input-only pin. Digital levels
O	Output. Digital levels
I/O	I/O is a bidirectional input/output signal
AI	Input. Analog levels
PWR	Power
GND	Ground
NC	Not Connected

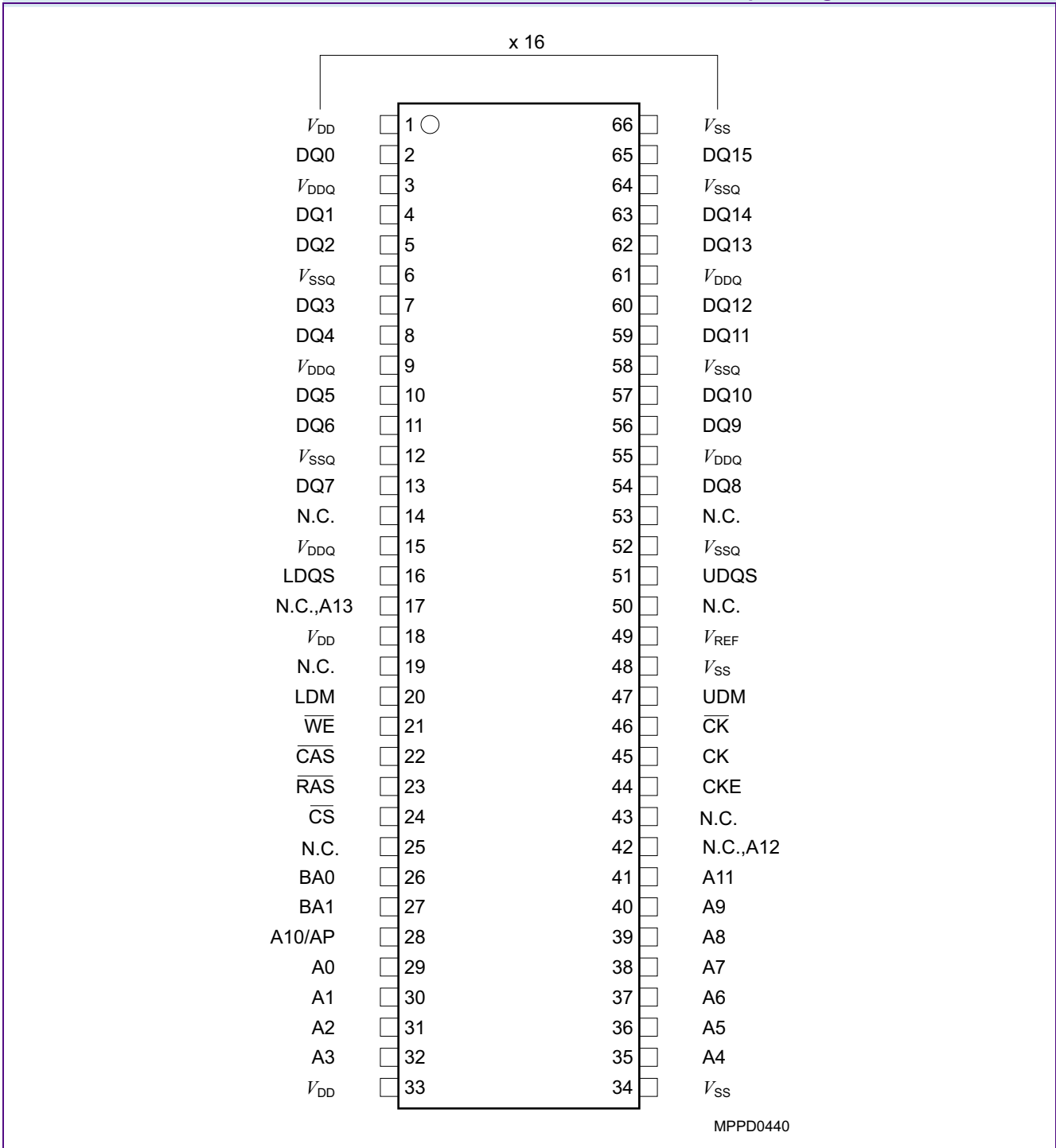
**TABLE 5**  
**Abbreviations for Buffer Type**

Abbreviation	Description
SSTL	Serial Stub Terminated Logic (SSTL2)
LV-CMOS	Low Voltage CMOS
CMOS	CMOS Levels
OD	Open Drain. The corresponding pin has 2 operational states, active low and tristate, and allows multiple devices to share as a wire-OR



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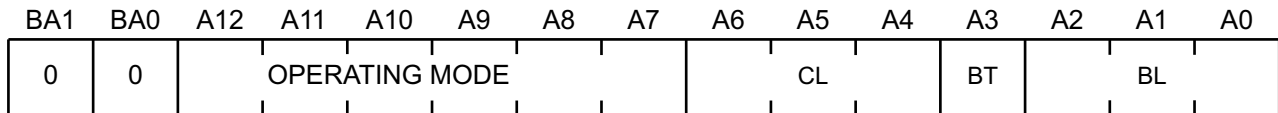
**FIGURE 1**  
Chip Configuration PG-TSOPII-66







### 3 Functional Description



MPBD2090

Field	Bits	Type <sup>1)</sup>	Description
<b>BL</b>	[2:0]	W	<b>Burst Length</b> Number of sequential bits per DQ related to one read/write command. <i>Note: All other bit combinations are RESERVED.</i>  001 2 010 4 010 8
<b>BT</b>	3		<b>Burst Type</b> See <a href="#">Table 6</a> for internal address sequence of low order address bits. 0 Sequential 1 Sequential
<b>CL</b>	[6:4]		<b>CAS Latency</b> Number of full clocks from read command to first data valid window. <i>Note: All other bit combinations are RESERVED.</i>  011 3
<b>MODE</b>	[12:7]		<b>Operating Mode</b> <i>Note: All other bit combinations are RESERVED.</i>  000000 Normal Operation without DLL Reset 000010 Normal Operation with DLL Reset

1) W = write only register bit



**TABLE 6**  
**Burst Definition**

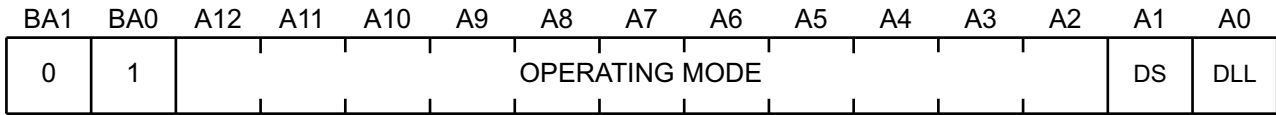
Burst Length	Starting Column Address			Order of Accesses Within a Burst	
	A2	A1	A0	Type = Sequential	Type = Interleaved
2			0	0-1	0-1
			1	1-0	1-0
4		0	0	0-1-2-3	0-1-2-3
		0	1	1-2-3-0	1-0-3-2
		1	0	2-3-0-1	2-3-0-1
		1	1	3-0-1-2	3-2-1-0
8	0	0	0	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7
	0	0	1	1-2-3-4-5-6-7-0	1-0-3-2-5-4-7-6
	0	1	0	2-3-4-5-6-7-0-1	2-3-0-1-6-7-4-5
	0	1	1	3-4-5-6-7-0-1-2	3-2-1-0-7-6-5-4
	1	0	0	4-5-6-7-0-1-2-3	4-5-6-7-0-1-2-3
	1	0	1	5-6-7-0-1-2-3-4	5-4-7-6-1-0-3-2
	1	1	0	6-7-0-1-2-3-4-5	6-7-4-5-2-3-0-1
	1	1	1	7-0-1-2-3-4-5-6	7-6-5-4-3-2-1-0

**Notes**

1. For a burst length of two, A1-Ai selects the two-data-element block; A0 selects the first access within the block.
2. For a burst length of four, A2-Ai selects the four-data-element block; A0-A1 selects the first access within the block.
3. For a burst length of eight, A3-Ai selects the eight-data-element block; A0-A2 selects the first access within the block.
4. Whenever a boundary of the block is reached within a given sequence above, the following access wraps within the block.



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MPBD2100

Field	Bits	Type <sup>1)</sup>	Description
DLL	0	W	<b>DLL Status</b> 0 <sub>B</sub> <b>Enabled</b> 1 <sub>B</sub> <b>Disabled</b>
DS	1		<b>Drive Strength</b> 0 <sub>B</sub> <b>Normal</b> 1 <sub>B</sub> <b>Weak</b>
MODE	[12:2]		<b>Operating Mode</b> <i>Note: All other bit combinations are RESERVED.</i> 0000000000 <sub>B</sub> <b>Normal Operation</b>

1) W = write only register bit

**TABLE 7**  
Truth Table 1a: Commands

Name (Function)	CS	RAS	CAS	WE	Address	MNE	Note
Deselect (NOP)	H	X	X	X	X	NOP	1)2)
No Operation (NOP)	L	H	H	H	X	NOP	1)2)
Active (Select Bank And Activate Row)	L	L	H	H	Bank/Row	ACT	1)3)
Read (Select Bank And Column, And Start Read Burst)	L	H	L	H	Bank/Col	Read	1)4)
Write (Select Bank And Column, And Start Write Burst)	L	H	L	L	Bank/Col	Write	1)4)
Burst Terminate	L	H	H	L	X	BST	1)5)
Precharge (Deactivate Row In Bank Or Banks)	L	L	H	L	Code	PRE	1)6)
Auto Refresh Or Self Refresh (Enter Self Refresh Mode)	L	L	L	H	X	AR/SR	1)7)8)
Mode Register Set	L	L	L	L	Op-Code	MRS	1)9)

- 1) CKE is HIGH for all commands shown except Self Refresh.  $V_{REF}$  must be maintained during Self Refresh operation
- 2) Deselect and NOP are functionally interchangeable.
- 3) BA0-BA1 provide bank address and A0-A12 provide row address.
- 4) BA0, BA1 provide bank address; A0-Ai provide column address (where i = 8 for x16); A10 HIGH enables the Auto Precharge feature (nonpersistent), A10 LOW disables the Auto Precharge feature.
- 5) Applies only to read bursts with Auto Precharge disabled; this command is undefined (and should not be used) for read bursts with Auto Precharge enabled or for write bursts.
- 6) A10 LOW: BA0, BA1 determine which bank is precharged. A10 HIGH: all banks are precharged and BA0, BA1 are "Don't Care".
- 7) This command is Auto Refresh if CKE is HIGH; Self Refresh if CKE is LOW.
- 8) Internal refresh counter controls row and bank addressing; all inputs and I/Os are "Don't Care" except for CKE.
- 9) BA0, BA1 select either the Base or the Extended Mode Register (BA0 = 0, BA1 = 0 selects Mode Register; BA0 = 1, BA1 = 0 selects Extended Mode Register; other combinations of BA0-BA1 are reserved; A0-A12 provide the op-code to be written to the selected Mode Register).

**TABLE 8**  
Truth Table 1b: DM Operation

Name (Function)	DM	DQs	Note
Write Enable	L	Valid	1)
Write Inhibit	H	X	

1) Used to mask write data; provided coincident with the corresponding data.

**TABLE 9**  
Truth Table 2: Clock Enable (CKE)

Current State	CKE n-1	CKEn	Command n	Action n	Note
	Previous Cycle	Current Cycle			
Self Refresh	L	L	X	Maintain Self-Refresh	1)
Self Refresh	L	H	Deselect or NOP	Exit Self-Refresh	2)
Power Down	L	L	X	Maintain Power-Down	–
Power Down	L	H	Deselect or NOP	Exit Power-Down	–
All Banks Idle	H	L	Deselect or NOP	Precharge Power-Down Entry	–
All Banks Idle	H	L	AUTO REFRESH	Self Refresh Entry	–
Bank(s) Active	H	L	Deselect or NOP	Active Power-Down Entry	–
	H	H	See <b>Table 10</b>	–	–

1)  $V_{REF}$  must be maintained during Self Refresh operation

2) Deselect or NOP commands should be issued on any clock edges occurring during the Self Refresh Exit ( $t_{XSNR}$ ) period. A minimum of 200 clock cycles are needed before applying a read command to allow the DLL to lock to the input clock.

#### Notes

1.  $CKEn$  is the logic state of CKE at clock edge  $n$ ;  $CKE\ n-1$  was the state of CKE at the previous clock edge.
2. Current state is the state of the DDR SGRAM immediately prior to clock edge  $n$ .
3.  $COMMAND\ n$  is the command registered at clock edge  $n$ , and  $ACTION\ n$  is a result of  $COMMAND\ n$ .
4. All states and sequences not shown are illegal or reserved.



**TABLE 10**

**Truth Table 3: Current State Bank n - Command to Bank n (same bank)**

Current State	$\overline{CS}$	$\overline{RAS}$	$\overline{CAS}$	$\overline{WE}$	Command	Action	Note
Any	H	X	X	X	Deselect	NOP. Continue previous operation.	1)2)3)4)5)6)
	L	H	H	H	No Operation	NOP. Continue previous operation.	1) to 6)
Idle	L	L	H	H	Active	Select and activate row	1) to 6)
	L	L	L	H	AUTO REFRESH	–	1) to 7)
	L	L	L	L	MODE REGISTER SET	–	1) to 7)
Row Active	L	H	L	H	Read	Select column and start Read burst	1) to 6),8)
	L	H	L	L	Write	Select column and start Write burst	1) to 6),8)
	L	L	H	L	Precharge	Deactivate row in bank(s)	1) to 6),9)
Read (Auto Precharge Disabled)	L	H	L	H	Read	Select column and start new Read burst	1) to 6),8)
	L	L	H	L	Precharge	Truncate Read burst, start Precharge	1) to 6),9)
	L	H	H	L	BURST TERMINATE	BURST TERMINATE	1) to 6),10)
Write (Auto Precharge Disabled)	L	H	L	H	Read	Select column and start Read burst	1) to 6), 8),11)
	L	H	L	L	Write	Select column and start Write burst	1) to 6),8)
	L	L	H	L	Precharge	Truncate Write burst, start Precharge	1) to 6),9),11)

- 1) This table applies when CKE n-1 was HIGH and CKE n is HIGH (see **Table 9** and after  $t_{XSNR}/t_{XSRD}$  has been met (if the previous state was self refresh).
- 2) This table is bank-specific, except where noted, i.e., the current state is for a specific bank and the commands shown are those allowed to be issued to that bank when in that state. Exceptions are covered in the notes below.
- 3) Current state definitions:  
 Idle: The bank has been precharged, and  $t_{RP}$  has been met.  
 Row Active: A row in the bank has been activated, and  $t_{RCD}$  has been met. No data bursts/accesses and no register accesses are in progress.  
 Read: A Read burst has been initiated, with Auto Precharge disabled, and has not yet terminated or been terminated.  
 Write: A Write burst has been initiated, with Auto Precharge disabled, and has not yet terminated or been terminated.
- 4) The following states must not be interrupted by a command issued to the same bank.  
 Precharging: Starts with registration of a Precharge command and ends when  $t_{RP}$  is met. Once  $t_{RP}$  is met, the bank is in the idle state.  
 Row Activating: Starts with registration of an Active command and ends when  $t_{RCD}$  is met. Once  $t_{RCD}$  is met, the bank is in the “row active” state.  
 Read w/Auto Precharge Enabled: Starts with registration of a Read command with Auto Precharge enabled and ends when  $t_{RP}$  has been met. Once  $t_{RP}$  is met, the bank is in the idle state.  
 Write w/Auto Precharge Enabled: Starts with registration of a Write command with Auto Precharge enabled and ends when  $t_{RP}$  has been met. Once  $t_{RP}$  is met, the bank is in the idle state. Deselect or NOP commands, or allowable commands to the other bank should be issued on any clock edge occurring during these states. Allowable commands to the other bank are determined by its current state and according to **Table 11**.
- 5) The following states must not be interrupted by any executable command; Deselect or NOP commands must be applied on each positive clock edge during these states.  
 Refreshing: Starts with registration of an Auto Refresh command and ends when  $t_{RFC}$  is met. Once  $t_{RFC}$  is met, the DDR SGRAM is in the “all banks idle” state.  
 Accessing Mode Register: Starts with registration of a Mode Register Set command and ends when  $t_{MRD}$  has been met. Once  $t_{MRD}$  is met, the DDR SGRAM is in the “all banks idle” state.  
 Precharging All: Starts with registration of a Precharge All command and ends when  $t_{RP}$  is met. Once  $t_{RP}$  is met, all banks is in the idle state.
- 6) All states and sequences not shown are illegal or reserved.
- 7) Not bank-specific; requires that all banks are idle.
- 8) Reads or Writes listed in the Command/Action column include Reads or Writes with Auto Precharge enabled and Reads or Writes with Auto Precharge disabled.
- 9) May or may not be bank-specific; if all/any banks are to be precharged, all/any must be in a valid state for precharging.



- 10) Not bank-specific; BURST TERMINATE affects the most recent Read burst, regardless of bank.
- 11) Requires appropriate DM masking.

**TABLE 11**

**Truth Table 4: Current State Bank n - Command to Bank m (different bank)**

Current State	$\overline{CS}$	$\overline{RAS}$	$\overline{CAS}$	$\overline{WE}$	Command	Action	Note
Any	H	X	X	X	Deselect	NOP. Continue previous operation.	1)2)3)4)5)6)
	L	H	H	H	No Operation	NOP. Continue previous operation.	1) to 6)
Idle	X	X	X	X	Any Command Otherwise Allowed to Bank m	–	1) to 6)
Row Activating, Active, or Precharging	L	L	H	H	Active	Select and activate row	1) to 6)
	L	H	L	H	Read	Select column and start Read burst	1) to 7)
	L	H	L	L	Write	Select column and start Write burst	1) to 7)
	L	L	H	L	Precharge	–	1) to 6)
Read (Auto Precharge Disabled)	L	L	H	H	Active	Select and activate row	1) to 6)
	L	H	L	H	Read	Select column and start new Read burst	1) to 7)
	L	L	H	L	Precharge	–	1) to 6)
Write (Auto Precharge Disabled)	L	L	H	H	Active	Select and activate row	1) to 6)
	L	H	L	H	Read	Select column and start Read burst	1) to 8)
	L	H	L	L	Write	Select column and start new Write burst	1) to 7)
	L	L	H	L	Precharge	–	1) to 6)
Read (With Auto Precharge)	L	L	H	H	Active	Select and activate row	1) to 6)
	L	H	L	H	Read	Select column and start new Read burst	1) to 7),9)
	L	H	L	L	Write	Select column and start Write burst	1) to 7),9),10)
	L	L	H	L	Precharge	–	1) to 6)
Write (With Auto Precharge)	L	L	H	H	Active	Select and activate row	1) to 6)
	L	H	L	H	Read	Select column and start Read burst	1) to 7),9)
	L	H	L	L	Write	Select column and start new Write burst	1) to 7),9)
	L	L	H	L	Precharge	–	1) to 6)

- 1) This table applies when CKE n-1 was HIGH and CKE n is HIGH (see **Table 9**: Clock Enable (CKE) and after  $t_{XSNR}/t_{XSRD}$  has been met (if the previous state was self refresh).
- 2) This table describes alternate bank operation, except where noted, i.e., the current state is for bank n and the commands shown are those allowed to be issued to bank m (assuming that bank m is in such a state that the given command is allowable). Exceptions are covered in the notes below.
- 3) Current state definitions:  
 Idle: The bank has been precharged, and  $t_{RP}$  has been met.  
 Row Active: A row in the bank has been activated, and  $t_{RCD}$  has been met. No data bursts/accesses and no register accesses are in progress.  
 Read: A Read burst has been initiated, with Auto Precharge disabled, and has not yet terminated or been terminated.  
 Write: A Write burst has been initiated, with Auto Precharge disabled, and has not yet terminated or been terminated.  
 Read with Auto Precharge Enabled: See <sup>10)</sup>.  
 Write with Auto Precharge Enabled: See <sup>10)</sup>.
- 4) AUTO REFRESH and Mode Register Set commands may only be issued when all banks are idle.
- 5) A BURST TERMINATE command cannot be issued to another bank; it applies to the bank represented by the current state only.
- 6) All states and sequences not shown are illegal or reserved.
- 7) Reads or Writes listed in the Command/Action column include Reads or Writes with Auto Precharge enabled and Reads or Writes with Auto Precharge disabled.



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- 8) Requires appropriate DM masking.
- 9) **Concurrent Auto Precharge:** This device supports "Concurrent Auto Precharge". When a read with auto precharge or a write with auto precharge is enabled any command may follow to the other banks as long as that command does not interrupt the read or write data transfer and all other limitations apply (e.g. contention between READ data and WRITE data must be avoided). The minimum delay from a read or write command with auto precharge enable, to a command to a different banks is summarized in **Table 12**.
- 10) A Write command may be applied after the completion of data output.

**TABLE 12****Truth Table 5: Concurrent Auto Precharge**

From Command	To Command (different bank)	Minimum Delay with Concurrent Auto Precharge Support	Unit
WRITE w/AP	Read or Read w/AP	$1 + (BL/2) + t_{WTR}$	$t_{CK}$
	Write to Write w/AP	$BL/2$	$t_{CK}$
	Precharge or Activate	1	$t_{CK}$
Read w/AP	Read or Read w/AP	$BL/2$	$t_{CK}$
	Write or Write w/AP	$CL \text{ (rounded up)} + BL/2$	$t_{CK}$
	Precharge or Activate	1	$t_{CK}$



# 4 Electrical Characteristics

## 4.1 Operating Conditions

**TABLE 13**  
Absolute Maximum Ratings

Parameter	Symbol	Values			Unit	Note/ Test Condition
		Min.	Typ.	Max.		
Voltage on I/O pins relative to $V_{SS}$	$V_{IN}, V_{OUT}$	-0.5	—	$V_{DDQ} + 0.5$	V	—
Voltage on inputs relative to $V_{SS}$	$V_{IN}$	-1	—	+3.6	V	—
Voltage on $V_{DD}$ supply relative to $V_{SS}$	$V_{DD}$	-1	—	+3.6	V	—
Voltage on $V_{DDQ}$ supply relative to $V_{SS}$	$V_{DDQ}$	-1	—	+3.6	V	—
Operating temperature (ambient)	$T_A$	0	—	+70	°C	—
Storage temperature (plastic)	$T_{STG}$	-55	—	+150	°C	—
Power dissipation (per SDRAM component)	$P_D$	—	1	—	W	—
Short circuit output current	$I_{OUT}$	—	50	—	mA	—

**Attention:** Stresses above the max. values listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Maximum ratings are absolute ratings; exceeding only one of these values may cause irreversible damage to the integrated circuit.

**TABLE 14**  
Input and Output Capacitances

Parameter	Symbol	Values			Unit	Note/ Test Condition
		Min.	Typ.	Max.		
Input Capacitance: CK, $\overline{CK}$	$C_{I1}$	2.0	—	3.0	pF	<sup>1)</sup>
Delta Input Capacitance	$C_{dl1}$	—	—	0.25	pF	<sup>1)</sup>
Input Capacitance: All other input-only pins	$C_{I2}$	2.0	—	3.0	pF	<sup>1)</sup>
Delta Input Capacitance: All other input-only pins	$C_{dlIO}$	—	—	0.5	pF	<sup>1)</sup>
Input/Output Capacitance: DQ, DQS, DM	$C_{IO}$	4.0	—	5.0	pF	<sup>1)2)</sup>
Delta Input/Output Capacitance: DQ, DQS, DM	$C_{dlIO}$	—	—	0.5	pF	<sup>1)</sup>

- 1) These values are guaranteed by design and are tested on a sample base only.  $V_{DDQ} = V_{DD} = 2.5 V \pm 0.2 V$ ,  $f = 100 MHz$ ,  $T_A = 25 °C$ ,  $V_{OUT(DC)} = V_{DDQ}/2$ ,  $V_{OUT}$  (Peak to Peak) 0.2 V. Unused pins are tied to ground.
- 2) DM inputs are grouped with I/O pins reflecting the fact that they are matched in loading to DQ and DQS to facilitate trace matching at the board level.





**TABLE 15**  
**Electrical Characteristics and DC Operating Conditions**

Parameter	Symbol	Values			Unit	Note <sup>1)</sup> /Test Condition
		Min.	Typ.	Max.		
Device Supply Voltage	$V_{DD}$	2.3	2.5	2.7	V	$f_{CK} \leq 166$ MHz
Device Supply Voltage	$V_{DD}$	2.5	2.6	2.7	V	$f_{CK} > 166$ MHz <sup>2)</sup>
Output Supply Voltage	$V_{DDQ}$	2.3	2.5	2.7	V	$f_{CK} \leq 166$ MHz <sup>3)</sup>
Output Supply Voltage	$V_{DDQ}$	2.5	2.6	2.7	V	$f_{CK} > 166$ MHz <sup>2)3)</sup>
Supply Voltage, I/O Supply Voltage	$V_{SS}, V_{SSQ}$	0		0	V	—
Input Reference Voltage	$V_{REF}$	$0.49 \times V_{DDQ}$	$0.5 \times V_{DDQ}$	$0.51 \times V_{DDQ}$	V	<sup>4)</sup>
I/O Termination Voltage (System)	$V_{TT}$	$V_{REF} - 0.04$	—	$V_{REF} + 0.04$	V	<sup>5)</sup>
Input High (Logic1) Voltage	$V_{IH(DC)}$	$V_{REF} + 0.15$	—	$V_{DDQ} + 0.3$	V	<sup>6)</sup>
Input Low (Logic0) Voltage	$V_{IL(DC)}$	-0.3	—	$V_{REF} - 0.15$	V	<sup>6)</sup>
Input Voltage Level, CK and CK Inputs	$V_{IN(DC)}$	-0.3	—	$V_{DDQ} + 0.3$	V	<sup>6)</sup>
Input Differential Voltage, CK and $\overline{CK}$ Inputs	$V_{ID(DC)}$	0.36	—	$V_{DDQ} + 0.6$	V	<sup>6)7)</sup>
VI-Matching Pull-up Current to Pull-down Current	$V_{IRatio}$	0.71	—	1.4	—	<sup>8)</sup>
Input Leakage Current	$I_I$	-2	—	2	$\mu$ A	Any input $0\text{ V} \leq V_{IN} \leq V_{DD}$ ; All other pins not under test = $0\text{ V}$ <sup>9)</sup>
Output Leakage Current	$I_{OZ}$	-5	—	5	$\mu$ A	DQs are disabled; $0\text{ V} \leq V_{OUT} \leq V_{DDQ}$ <sup>9)</sup>
Output High Current, Normal Strength Driver	$I_{OH}$	—	—	-16.2	mA	$V_{OUT} = 1.95\text{ V}$
Output Low Current, Normal Strength Driver	$I_{OL}$	16.2	—	—	mA	$V_{OUT} = 0.35\text{ V}$

- 1)  $0\text{ }^\circ\text{C} \leq T_A \leq 70\text{ }^\circ\text{C}$ ;  $V_{DDQ} = 2.5\text{ V} \pm 0.2\text{ V}$ ,  $V_{DD} = +2.5\text{ V} \pm 0.2\text{ V}$ .
- 2) DDR400 conditions apply for all clock frequencies above 166 MHz.
- 3) Under all conditions,  $V_{DDQ}$  must be less than or equal to  $V_{DD}$ .
- 4) Peak to peak AC noise on  $V_{REF}$  may not exceed  $\pm 2\%$   $V_{REF,DC}$ .  $V_{REF}$  is also expected to track noise variations in  $V_{DDQ}$ .
- 5)  $V_{TT}$  is not applied directly to the device.  $V_{TT}$  is a system supply for signal termination resistors, is expected to be set equal to  $V_{REF}$ , and must track variations in the DC level of  $V_{REF}$ .
- 6) Inputs are not recognized as valid until  $V_{REF}$  stabilizes.
- 7)  $V_{ID}$  is the magnitude of the difference between the input level on CK and the input level on  $\overline{CK}$ .
- 8) The ratio of the pull-up current to the pull-down current is specified for the same temperature and voltage, over the entire temperature and voltage range, for device drain to source voltage from 0.25 to 1.0 V. For a given output, it represents the maximum difference between pull-up and pull-down drivers due to process variation.
- 9) Values are shown per pin.



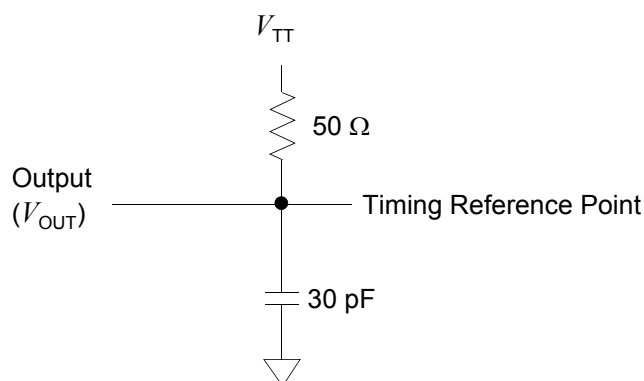
## 4.2 AC Characteristics

(Notes 1-5 apply to the following Tables; Electrical Characteristics and DC Operating Conditions, AC Operating Conditions,  $I_{DD}$  Specifications and Conditions, and Electrical Characteristics and AC Timing.)

### Notes

1. All voltages referenced to  $V_{SS}$ .
2. Tests for AC timing,  $I_{DD}$ , and electrical, AC and DC characteristics, may be conducted at nominal reference/supply voltage levels, but the related specifications and device operation are guaranteed for the full voltage range specified.
3. **Figure 2** represents the timing reference load used in defining the relevant timing parameters of the part. It is not intended to be either a precise representation of the typical system environment nor a depiction of the actual load presented by a production tester. System designers will use IBIS or other simulation tools to correlate the timing reference load to a system environment. Manufacturers will correlate to their production test conditions (generally a coaxial transmission line terminated at the tester electronics).
4. AC timing and  $I_{DD}$  tests may use a  $V_{IL}$  to  $V_{IH}$  swing of up to 1.5 V in the test environment, but input timing is still referenced to  $V_{REF}$  (or to the crossing point for CK,  $\overline{CK}$ ), and parameter specifications are guaranteed for the specified AC input levels under normal use conditions. The minimum slew rate for the input signals is 1 V/ns in the range between  $V_{IL(AC)}$  and  $V_{IH(AC)}$ .
5. The AC and DC input level specifications are as defined in the SSTL\_2 Standard (i.e. the receiver effectively switches as a result of the signal crossing the AC input level, and remains in that state as long as the signal does not ring back above (below) the DC input LOW (HIGH) level).
6. For System Characteristics like Setup & Holdtime Derating for Slew Rate, I/O Delta Rise/Fall Derating, DDR SGRAM Slew Rate Standards, Overshoot & Undershoot specification and Clamp  $V-I$  characteristics see the latest Industry specification for DDR components.

**FIGURE 2**  
AC Output Load Circuit Diagram / Timing Reference Load





**TABLE 16**  
**AC Operating Conditions**

Parameter	Symbol	Values		Unit	Note/ Test Condition
		Min.	Max.		
Input High (Logic 1) Voltage, DQ, DQS and DM Signals	$V_{IH(AC)}$	$V_{REF} + 0.31$	—	V	1)2)3)
Input Low (Logic 0) Voltage, DQ, DQS and DM Signals	$V_{IL(AC)}$	—	$V_{REF} - 0.31$	V	1)2)3)
Input Differential Voltage, CK and $\overline{CK}$ Inputs	$V_{ID(AC)}$	0.7	$V_{DDQ} + 0.6$	V	1)2)3)4)
Input Closing Point Voltage, CK and $\overline{CK}$ Inputs	$V_{IX(AC)}$	$0.5 \times V_{DDQ} - 0.2$	$0.5 \times V_{DDQ} + 0.2$	V	1)2)3)5)

- 1)  $V_{DDQ} = 2.5\text{ V} \pm 0.2\text{ V}$ ,  $V_{DD} = +2.5\text{ V} \pm 0.2\text{ V}$  (DDR200 - DDR333);  $V_{DDQ} = 2.6\text{ V} \pm 0.1\text{ V}$ ,  $V_{DD} = +2.6\text{ V} \pm 0.1\text{ V}$  (DDR400);  $0\text{ }^\circ\text{C} \leq T_A \leq 70\text{ }^\circ\text{C}$
- 2) Input slew rate = 1 V/ns.
- 3) Inputs are not recognized as valid until  $V_{REF}$  stabilizes.
- 4)  $V_{ID}$  is the magnitude of the difference between the input level on CK and the input level on  $\overline{CK}$ .
- 5) The value of  $V_{IX}$  is expected to equal  $0.5 \times V_{DDQ}$  of the transmitting device and must track variations in the DC level of the same.

**TABLE 17**  
**AC Timing - Absolute Specifications**

Parameter	Symbol	-4		-5		-6		Unit	Note <sup>1)</sup> / Test Condition
		DDR500		DDR400B		DDR333			
		Min.	Max.	Min.	Max.	Min.	Max.		
DQ output access time from CK/ $\overline{CK}$	$t_{AC}$	-0.6	+0.6	-0.65	+0.65	-0.7	+0.7	ns	2)3)4)5)
CK high-level width	$t_{CH}$	0.45	0.55	0.45	0.55	0.45	0.55	$t_{CK}$	2)3)4)5)
Clock cycle time	$t_{CK}$	4	12	5	12	6	12	ns	CL = 3.0 2)3)4)5)
CK low-level width	$t_{CL}$	0.45	0.55	0.45	0.55	0.45	0.55	$t_{CK}$	2)3)4)5)
Auto precharge write recovery + precharge time	$t_{DAL}$	28	—	35	—	$(t_{WR}/t_{CK}) + (t_{RP}/t_{CK})$		$t_{CK}$	2)3)4)5)6)
DQ and DM input hold time	$t_{DH}$	0.4	—	0.4	—	0.45	—	ns	2)3)4)5)
DQ and DM input pulse width (each input)	$t_{DIPW}$	1.75	—	1.75	—	1.75	—	ns	2)3)4)5)6)
DQS output access time from CK/ $\overline{CK}$	$t_{DQSCK}$	-0.65	+0.65	-0.65	+0.65	-0.6	+0.6	ns	2)3)4)5)
DQS input low (high) pulse width (write cycle)	$t_{DQSL,H}$	0.35	—	0.35	—	0.35	—	$t_{CK}$	2)3)4)5)
DQS-DQ skew (DQS and associated DQ signals)	$t_{DQSQ}$	—	0.5	—	0.5	—	0.45	ns	TSOPII 2)3)4)5)



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Parameter	Symbol	-4		-5		-6		Unit	Note <sup>1)</sup> / Test Condition
		DDR500		DDR400B		DDR333			
		Min.	Max.	Min.	Max.	Min.	Max.		
Write command to 1 <sup>st</sup> DQS latching transition	$t_{DQSS}$	0.85	1.15	0.75	1.25	0.75	1.25	$t_{CK}$	2)3)4)5)
DQ and DM input setup time	$t_{DS}$	0.4	—	0.4	—	0.45	—	ns	2)3)4)5)
DQS falling edge hold time from CK (write cycle)	$t_{DSH}$	0.2	—	0.2	—	0.2	—	$t_{CK}$	2)3)4)5)
DQS falling edge to CK setup time (write cycle)	$t_{DSS}$	0.2	—	0.2	—	0.2	—	$t_{CK}$	2)3)4)5)
Clock Half Period	$t_{HP}$	min. ( $t_{CL}$ , $t_{CH}$ )	—	min. ( $t_{CL}$ , $t_{CH}$ )	—	min. ( $t_{CL}$ , $t_{CH}$ )	—	ns	2)3)4)5)
Data-out high-impedance time from CK/ $\overline{CK}$	$t_{HZ}$	—	+0.7	—	+0.7	—	+0.7	ns	2)3)4)5)7)
Address and control input hold time	$t_{IH}$	0.6	—	0.6	—	0.75	—	ns	fast slew rate 3)4)5)6)8)
		0.7	—	0.7	—	0.8	—	ns	slow slew rate <sup>3)4)5)6)8)</sup>
Control and Addr. input pulse width (each input)	$t_{IPW}$	2.2	—	2.2	—	2.2	—	ns	2)3)4)5)9)
Address and control input setup time	$t_{IS}$	0.6	—	0.6	—	0.75	—	ns	fast slew rate 3)4)5)6)8)
		0.7	—	0.7	—	0.8	—	ns	slow slew rate <sup>3)4)5)6)8)</sup>
Data-out low-impedance time from CK/ $\overline{CK}$	$t_{LZ}$	-0.7	+0.7	-0.7	+0.7	-0.7	+0.7	ns	2)3)4)5)7)
Mode register set command cycle time	$t_{MRD}$	2	—	2	—	2	—	$t_{CK}$	2)3)4)5)
DQ/DQS output hold time from DQS	$t_{QH}$	$t_{HP} - t_{QHS}$	—	$t_{HP} - t_{QHS}$	—	$t_{HP} - t_{QHS}$	—	ns	2)3)4)5)
Data hold skew factor	$t_{QHS}$	—	0.4	—	0.5	—	0.55	ns	TSOPII <sup>2)3)4)5)</sup>
Active to Autoprecharge delay	$t_{RAP}$	16	—	20	—	$t_{RCD}$	—	ns	2)3)4)5)
Active to Precharge command	$t_{RAS}$	36	70E+3	40	70E+3	42	70E+3	ns	2)3)4)5)



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Parameter	Symbol	-4		-5		-6		Unit	Note <sup>1)</sup> / Test Condition
		DDR500		DDR400B		DDR333			
		Min.	Max.	Min.	Max.	Min.	Max.		
Active to Active/Auto-refresh command period	$t_{RC}$	52	—	55	—	60	—	ns	2)3)4)5)
Active to Read delay	$t_{RCDRD}$	16	—	20	—	18	—	ns	2)3)4)5)
Active to Write delay	$t_{RCDWR}$	12	—	15	—	18	—	ns	2)3)4)5)
Average Periodic Refresh Interval	$t_{REFI}$	—	7.8	—	7.8	—	7.8	$\mu$ s	2)3)4)5)8)
Precharge command period	$t_{RP}$	16	—	20	—	18	—	ns	2)3)4)5)
Read preamble	$t_{RPRE}$	0.9	1.1	0.9	1.1	0.9	1.1	$t_{CK}$	2)3)4)5)
Read postamble	$t_{RPST}$	0.4	0.6	0.4	0.6	0.4	0.6	$t_{CK}$	2)3)4)5)
Active bank A to Active bank B command	$t_{RRD}$	8	—	10	—	12	—	ns	2)3)4)5)
Write preamble	$t_{WPRE}$	0.25	—	0.25	—	0.25	—	$t_{CK}$	2)3)4)5)
Write preamble setup time	$t_{WPRES}$	0	—	0	—	0	—	ns	2)3)4)5)10)
Write postamble	$t_{WPST}$	0.4	0.6	0.4	0.6	0.4	0.6	$t_{CK}$	2)3)4)5)11)
Write recovery time	$t_{WR}$	15	—	15	—	15	—	ns	2)3)4)5)
Internal write to read command delay	$t_{WTR}$	1	—	1	—	1	—	$t_{CK}$	2)3)4)5)
Exit self-refresh to non-read command	$t_{XSNR}$	75	—	75	—	75	—	ns	2)3)4)5)
Exit self-refresh to read command	$t_{XSRD}$	200	—	200	—	200	—	$t_{CK}$	2)3)4)5)

- 1)  $0\text{ }^{\circ}\text{C} \leq T_A \leq 70\text{ }^{\circ}\text{C}$ ;  $V_{DDQ} = 2.5\text{ V} \pm 0.2\text{ V}$ ,  $V_{DD} = +2.5\text{ V} \pm 0.2\text{ V}$  (DDR333);  $V_{DDQ} = 2.6\text{ V} \pm 0.1\text{ V}$ ,  $V_{DD} = +2.6\text{ V} \pm 0.1\text{ V}$  (DDR400)
- 2) Input slew rate  $\geq 1\text{ V/ns}$  for DDR400, DDR333
- 3) The CK/ $\overline{\text{CK}}$  input reference level (for timing reference to CK/ $\overline{\text{CK}}$ ) is the point at which CK and  $\overline{\text{CK}}$  cross: the input reference level for signals other than CK/ $\overline{\text{CK}}$ , is  $V_{REF}$ . CK/ $\overline{\text{CK}}$  slew rate are  $\geq 1.0\text{ V/ns}$ .
- 4) Inputs are not recognized as valid until  $V_{REF}$  stabilizes.
- 5) The Output timing reference level, as measured at the timing reference point indicated in AC Characteristics (note 3) is  $V_{TT}$ .
- 6) For each of the terms, if not already an integer, round to the next highest integer.  $t_{CK}$  is equal to the actual system clock cycle time.
- 7)  $t_{HZ}$  and  $t_{LZ}$  transitions occur in the same access time windows as valid data transitions. These parameters are not referred to a specific voltage level, but specify when the device is no longer driving (HZ), or begins driving (LZ).
- 8) Fast slew rate  $\geq 1.0\text{ V/ns}$ , slow slew rate  $\geq 0.5\text{ V/ns}$  and  $< 1\text{ V/ns}$  for command/address and CK &  $\overline{\text{CK}}$  slew rate  $> 1.0\text{ V/ns}$ , measured between  $V_{IH(ac)}$  and  $V_{IL(ac)}$ .
- 9) These parameters guarantee device timing, but they are not necessarily tested on each device.
- 10) The specific requirement is that DQS be valid (HIGH,LOW, or some point on a valid transition) on or before this CK edge. A valid transition is defined as monotonic and meeting the input slew rate specifications of the device. When no writes were previously in progress on the bus, DQS will be transitioning from Hi-Z to logic LOW. If a previous write was in progress, DQS could be HIGH, LOW at this time, depending on  $t_{DQSS}$ .
- 11) The maximum limit for this parameter is not a device limit. The device operates with a greater value for this parameter, but system performance (bus turnaround) degrades accordingly.



**TABLE 18**  
 **$I_{DD}$  Conditions**

Parameter	Symbol
<b>Operating Current:</b> one bank; active/ precharge; $t_{RC} = t_{RCMIN}$ ; $t_{CK} = t_{CKMIN}$ ; DQ, DM, and DQS inputs changing once per clock cycle; address and control inputs changing once every two clock cycles.	$I_{DD0}$
<b>Operating Current:</b> one bank; active/read/precharge; Burst = 4; Refer to the following page for detailed test conditions.	$I_{DD1}$
<b>Precharge Power-Down Standby Current:</b> all banks idle; power-down mode; $CKE \leq V_{ILMAX}$ ; $t_{CK} = t_{CKMIN}$	$I_{DD2P}$
<b>Precharge Floating Standby Current:</b> $\overline{CS} \geq V_{IHMIN}$ , all banks idle; $CKE \geq V_{IHMIN}$ ; $t_{CK} = t_{CKMIN}$ , address and other control inputs changing once per clock cycle, $V_{IN} = V_{REF}$ for DQ, DQS and DM.	$I_{DD2F}$
<b>Precharge Quiet Standby Current:</b> $\overline{CS} \geq V_{IHMIN}$ , all banks idle; $CKE \geq V_{IHMIN}$ ; $t_{CK} = t_{CKMIN}$ , address and other control inputs stable at $\geq V_{IHMIN}$ or $\leq V_{ILMAX}$ ; $V_{IN} = V_{REF}$ for DQ, DQS and DM.	$I_{DD2Q}$
<b>Active Power-Down Standby Current:</b> one bank active; power-down mode; $CKE \leq V_{ILMAX}$ ; $t_{CK} = t_{CKMIN}$ ; $V_{IN} = V_{REF}$ for DQ, DQS and DM.	$I_{DD3P}$
<b>Active Standby Current:</b> one bank active; $\overline{CS} \geq V_{IHMIN}$ ; $CKE \geq V_{IHMIN}$ ; $t_{RC} = t_{RASMAX}$ ; $t_{CK} = t_{CKMIN}$ ; DQ, DM and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	$I_{DD3N}$
<b>Operating Current:</b> one bank active; Burst = 2; reads; continuous burst; address and control inputs changing once per clock cycle; 50% of data outputs changing on every clock edge; CL = 2 for DDR200 and DDR266A, CL = 3 for DDR333; $t_{CK} = t_{CKMIN}$ ; $I_{OUT} = 0$ mA	$I_{DD4R}$
<b>Operating Current:</b> one bank active; Burst = 2; writes; continuous burst; address and control inputs changing once per clock cycle; 50% of data outputs changing on every clock edge; CL = 2 for DDR200 and DDR266A, CL = 3 for DDR333; $t_{CK} = t_{CKMIN}$	$I_{DD4W}$
<b>Auto-Refresh Current:</b> $t_{RC} = t_{RFCMIN}$ , burst refresh	$I_{DD5}$
<b>Self-Refresh Current:</b> $CKE \leq 0.2$ V; external clock on; $t_{CK} = t_{CKMIN}$	$I_{DD6}$
<b>Operating Current:</b> four bank; four bank interleaving with BL = 4; Refer to the following page for detailed test conditions.	$I_{DD7}$

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 **$I_{DD}$  Specification**

Symbol	-4	-5	-6	Unit	Note <sup>1)</sup> /Test Condition
$I_{DD0}$	115	75	65	mA	2)3)
$I_{DD1}$	135	95	80	mA	3)
$I_{DD2P}$	6	4	4	mA	3)
$I_{DD2F}$	45	30	25	mA	3)
$I_{DD2Q}$	35	20	17	mA	3)
$I_{DD3P}$	23	13	11	mA	3)
$I_{DD3N}$	65	43	36	mA	3)
$I_{DD4R}$	150	100	85	mA	3)
$I_{DD4W}$	160	100	90	mA	3)
$I_{DD5}$	240	140	120	mA	3)
$I_{DD6}$	2.8	1.4	1.4	mA	4)
$I_{DD7}$	315	210	180	mA	3)

1) Test conditions:  $V_{DD} = 2.7\text{ V}$ ,  $T_A = 10\text{ }^\circ\text{C}$

2)  $I_{DD}$  specifications are tested after the device is properly initialized and measured at 133 MHz for DDR266, 166 MHz for DDR333, and 200 MHz for DDR400, 250MHz for DDR500

3) Input slew rate = 1 V/ns

4) Enables on-chip refresh and address counters



## 4.3 Current Measurement Conditions

Legend: A = Activate, R = Read, P = Precharge, N = NOP

### $I_{DD1}$ : Operating Current: One Bank Operation, ACT- RD- PRE

1. General test condition
  - a) Only one bank is accessed with  $t_{RC,MIN}$
  - b) Burst Mode, Address and Control inputs on NOP edge are changing once per clock cycle
  - c) 50% of data changing at every burst
  - d)  $I_{OUT} = 0$  mA
2. Timing patterns
  - a) **DDR333** (166 MHz, CL = 2.5):  $t_{CK} = 6$  ns, BL = 4,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RC} = 10 \times t_{CK}$ ,  $t_{RAS} = 7 \times t_{CK}$   
Setup: A0 N N R0 N N N P0 N N  
Read : A0 N N R0 N N N P0 N N - repeat the same timing with random address changing
  - b) **DDR400A** (200 MHz, CL = 2.5):  $t_{CK} = 5$  ns, BL = 4,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RC} = 11 \times t_{CK}$ ,  $t_{RAS} = 8 \times t_{CK}$   
Setup: A0 N N R0 N N N N P0 N N  
Read : A0 N N R0 N N N N P0 N N - repeat the same timing with random address changing
  - c) **DDR500** (250 MHz, CL = 3):  $t_{CK} = 4$  ns, BL = 4,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RC} = 13 \times t_{CK}$ ,  $t_{RAS} = 10 \times t_{CK}$   
Setup: A0 N N R0 N N N N N P0 N N  
Read : A0 N N R0 N N N N N P0 N N - repeat the same timing with random address changing

### $I_{DD7}$ : Operating Current: Four Bank Operation

1. General test condition
  - a) Four banks are being interleaved with  $t_{RCMIN}$
  - b) Burst Mode, Address and Control inputs on NOP edge are not changing
  - c) 50% of data changing at every burst
  - d)  $I_{OUT} = 0$  mA
2. Timing patterns
  - a) **DDR333** (166 MHz, CL = 2.5):  $t_{CK} = 6$  ns, BL = 4,  $t_{RRD} = 2 \times t_{CK}$ ,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RAS} = 7 \times t_{CK}$ ,  $t_{RC} = 10 \times t_{CK}$   
Setup: A0 N A1 RA0 A2 RA1 A3 RA2 N RA3  
Read : A0 N A1 RA0 A2 RA1 A3 RA2 N RA3 - repeat the same timing with random address changing
  - b) **DDR400A** (200 MHz, CL = 2.5):  $t_{CK} = 5$  ns, BL = 4,  $t_{RRD} = 2 \times t_{CK}$ ,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RAS} = 8 \times t_{CK}$ ,  $t_{RC} = 11 \times t_{CK}$   
Setup: A0 N A1 RA0 A2 RA1 A3 RA2 N RA3 N N N  
Read : A0 N A1 RA0 A2 RA1 A3 RA2 N RA3 N N N - repeat the same timing with random address changing
  - c) **DDR500** (250MHz, CL=3):  $t_{CK} = 4$  ns, BL=4,  $t_{RRD} = 2 \times t_{CK}$ ,  $t_{RCD} = 3 \times t_{CK}$ ,  $t_{RAS} = 10 \times t_{CK}$ ,  $t_{RC} = 13 \times t_{CK}$   
Setup: A0 N A1 RA0 A2 RA1 A3 RA2 N RA3 N N N  
Read : A0 N A1 RA0 A2 RA1 A3 RA2 N RA3 N N N - repeat the same timing with random address changing

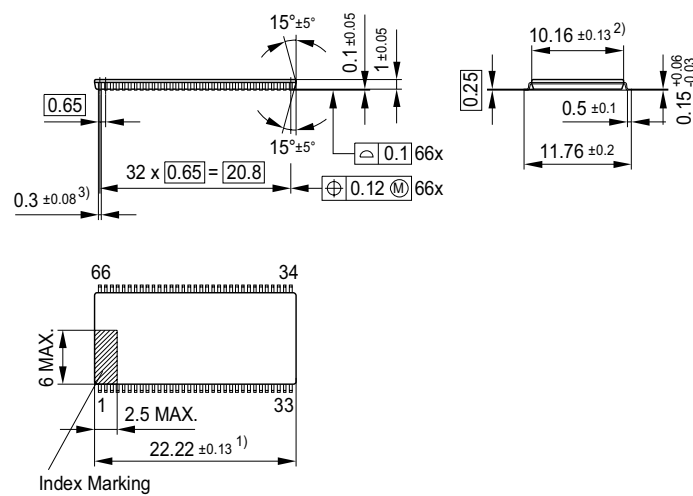




## 5 Package Outlines

There is package TSOPII-66 type used for this product family.

**FIGURE 3**  
Package Outline PG-TSOPII-66



- 1) Does not include plastic or metal protrusion of 0.15 max. per side
- 2) Does not include plastic protrusion of 0.25 max. per side
- 3) Does not include dambar protrusion of 0.13 max.

### Notes

1. Drawing according to ISO 8015
2. Dimensions in mm
3. General tolerances +/- 0.15



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